

Josef Prost

List of Publications by Year in descending order

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#	ARTICLE	IF	CITATIONS
1	Long short-term memory based semi-supervised encoderâ€”decoder for early prediction of failures in self-lubricating bearings. <i>Friction</i> , 2023, 11, 109-124.	6.4	10
2	Semi-Supervised Classification of the State of Operation in Self-Lubricating Journal Bearings Using a Random Forest Classifier. <i>Lubricants</i> , 2021, 9, 50.	2.9	14
3	Establishment of a high-capacity X-ray source in Austria for use in materials science. <i>Acta Crystallographica Section A: Foundations and Advances</i> , 2019, 75, e730-e730.	0.1	0
4	A first evaluation of the analytical capabilities of the new X-ray fluorescence facility at International Atomic Energy Agency-Elettra Sincrotrone Trieste for multipurpose total reflection X-ray fluorescence analysis. <i>Spectrochimica Acta, Part B: Atomic Spectroscopy</i> , 2018, 145, 8-19.	2.9	5
5	Dual energy-band excitation from a low power Rh anode X-ray tube for the simultaneous determination of low Z and high Z elements (Na-U) using total-reflection X-ray fluorescence analysis (TXRF). <i>Review of Scientific Instruments</i> , 2018, 89, 093108.	1.3	6
6	Evaluation of a sample preparation procedure for total-reflection X-ray fluorescence analysis of directly collected airborne particulate matter samples. <i>Spectrochimica Acta, Part B: Atomic Spectroscopy</i> , 2018, 147, 13-20.	2.9	10
7	Synchrotron radiation micro X-ray fluorescence spectroscopy of thin structures in bone samples: comparison of confocal and color X-ray camera setups. <i>Journal of Synchrotron Radiation</i> , 2017, 24, 307-311.	2.4	12
8	Quantitative total reflection X-ray fluorescence analysis of directly collected aerosol samples. <i>X-Ray Spectrometry</i> , 2017, 46, 454-460.	1.4	20
9	(Invited) ALD to Prevent Metal Transfer from Implants. <i>ECS Transactions</i> , 2016, 75, 167-175.	0.5	1
10	Comparison of different excitation modes for the analysis of light elements with a TXRF vacuum chamber. <i>Powder Diffraction</i> , 2015, 30, 93-98.	0.2	4
11	Atomic layer deposition to prevent metal transfer from implants: An X-ray fluorescence study. <i>Applied Surface Science</i> , 2015, 359, 215-220.	6.1	13
12	A novel vacuum spectrometer for total reflection x-ray fluorescence analysis with two exchangeable low power x-ray sources for the analysis of low, medium, and high Z elements in sequence. <i>Review of Scientific Instruments</i> , 2015, 86, 083105.	1.3	23
13	Nanoliter deposition unit for pipetting droplets of small volumes for Total Reflection X-ray Fluorescence applications. <i>Spectrochimica Acta, Part B: Atomic Spectroscopy</i> , 2013, 82, 71-75.	2.9	13
14	Production of the ideal sample shape for Total Reflection X-ray Fluorescence analysis. <i>Spectrochimica Acta, Part B: Atomic Spectroscopy</i> , 2012, 77, 31-34.	2.9	13